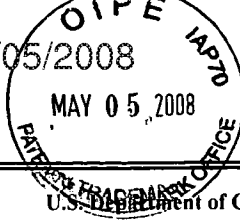


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							Yes No
TRANSLATION KEY: * English Abstract. ^F Concise statement of relevance provided in foreign search report. ^C Concise statement of relevance provided in specification or in attachment to document. ^S Concise statement of relevance provided in IDS. ^P Relevant portion of document translated. ^O English abstract only - copy of document in pct search.							
OTHER INFORMATION DISCLOSURE CITATIONS (Including Author, Title, Date, Pertinent Pages, Etc.)							
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EXAMINER Jennifer A. Smith /Jennifer Smith/				DATE CONSIDERED 11/02/2008			
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